High Speed, Dual Channel, 6A, 4.5 to 16V$_{OUT}$, Power MOSFET Driver

ISL89160, ISL89161, ISL89162

The ISL89160, ISL89162, and ISL89162 are high-speed, 6A, dual channel MOSFET drivers. These parts are identical to the ISL89163, ISL89164, ISL89165 drivers but without the enable inputs for each channel.

Precision thresholds on all logic inputs allow the use of external RC circuits to generate accurate and stable time delays on both inputs, INA and INB. This capability is very useful for dead time control.

At high switching frequencies, these MOSFET drivers use very little bias current. Separate, non-overlapping drive circuits are used to drive each CMOS output FET to prevent shoot-thru currents in the output stage.

The undervoltage lock-out (UV) insures that driver outputs remain off (low) until VDD is sufficiently high for correct logic control. This prevents unexpected behaviour when VDD is being turned on or turned off.

Features

- Dual output, 6A peak current (sink and source)
- Typical ON-resistance <1Ω
- Specified Miller plateau drive currents
- Very low thermal impedance (θ_{JC} = 3°C/W)
- 3.3V to 5V Logic Inputs with Hysteresis are VDD tolerant
- Precision threshold inputs for time delays with external RC components
- ~ 20ns rise and fall time driving a 10nF load.
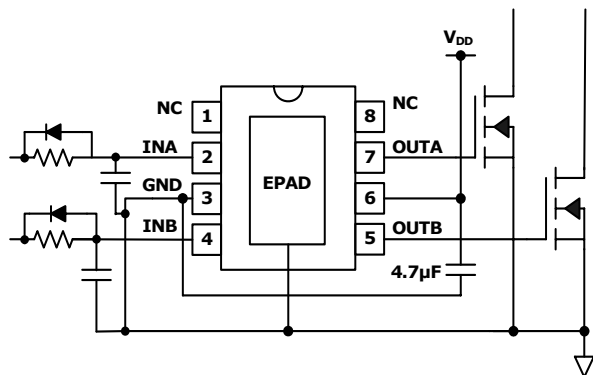- Low operating bias currents
- Pb-Free (RoHs Compliant)

Applications

- Synchronous Rectifier (SR) Driver
- Switch mode power supplies
- Motor Drives, Class D amplifiers, UPS, Inverters
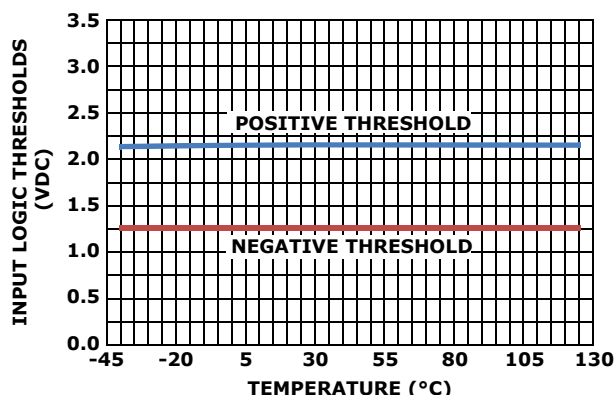- Pulse Transformer driver
- Clock/Line driver

Related Literature

- AN1602 "ISL8916xA, ISL8916xB, ISL8916xC, Evaluation Board User's Guide"
- AN1603 "ISL6752_54 Evaluation Board Application Note"

Typical Application

Temp Stable Logic Thresholds

Block Diagram

For clarity, only one channel is shown

For options A and B, the UV comparator holds off the outputs until V_{DD} ~> 3.3V_{DC}. For option C, the UV release is ~> 6.5V

Separate FET drives, with non-overlapping outputs, prevent shoot-thru currents in the output CMOS FETs resulting with very low high frequency operating currents.

V_{DD}

INx

ISL89160

ISL89161, ISL89162

OUTx

10k

EPAD

GND

For proper thermal and electrical performance, the EPAD must be connected to the PCB ground plane.

Pin Configurations

ISL89160FR, ISL89160FB
(8 LD TDFN, EPSOIC)
TOP VIEW

NC 1	8 NC
INA 2	7 OUTA
GND 3	6 VDD
INB 4	5 OUTB

ISL89161FR, ISL89161FB
(8 LD TDFN, EPSOIC)
TOP VIEW

NC 1	8 NC
/INA 2	7 OUTA
GND 3	6 VDD
/INB 4	5 OUTB

ISL89162FR, ISL89162FB
(8 LD TDFN, EPSOIC)
TOP VIEW

NC 1	8 NC
/INA 2	7 OUTA
GND 3	6 VDD
INB 4	5 OUTB

Pin Descriptions

PIN NUMBER	SYMBOL	DESCRIPTION
1	NC	No Connect. This pin may be left open or connected to 0V or VDD
2	INA or /INA	Channel A input, 0V to VDD
3	GND	Power Ground, 0V
4	INB or /INB	Channel B enable, 0V to VDD
5	OUTB	Channel B output
6	VDD	Power input, 4.5V to 16V
7	OUTA	Channel A output, 0V to VDD
8	NC	No Connect. This pin may be left open or connected to 0V or VDD
	EPAD	Power Ground, 0V

Ordering Information

PART NUMBER (Notes 1, 2, 3)	PART MARKING	TEMP RANGE (°C)	INPUT CONFIGURATION	PACKAGE (Pb-Free)	PKG. DWG. #
ISL89160FRTAZ	160A	-40 to +125	non-inverting	8 Ld 3x3 TDFN	L8.3x3I
ISL89161FRTAZ	161A	-40 to +125	inverting	8 Ld 3x3 TDFN	L8.3x3I
ISL89162FRTAZ	162A	-40 to +125	inverting + non-inverting	8 Ld 3x3 TDFN	L8.3x3I
ISL89160FBEAZ	89160 FBEAZ	-40 to +125	non-inverting	8 Ld EPSOIC	M8.15D
ISL89161FBEAZ	89161 FBEAZ	-40 to +125	inverting	8 Ld EPSOIC	M8.15D
ISL89162FBEAZ	89162 FBEAZ	-40 to +125	inverting + non-inverting	8 Ld EPSOIC	M8.15D

NOTES:

1. Add "-T*", suffix for tape and reel. Please refer to TB347 for details on reel specifications.

2. These Intersil Pb-free plastic packaged products employ special Pb-free material sets, molding compounds/die attach materials, and 100% matte tin plate plus anneal (e3 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations). Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020.

3. For Moisture Sensitivity Level (MSL), please see device information page for ISL89160, ISL89161, ISL89162. For more information on MSL, please see Technical Brief TB363.

ISL89160, ISL89161, ISL89162

Absolute Maximum Ratings

Supply Voltage, V_{DD} Relative to GND . . . . -0.3V to 18V
Logic Inputs (INA, INB) . . . . GND - 0.3v to V_{DD} + 0.3V
Outputs (OUTA, OUTB). . . . . GND - 0.3v to V_{DD} + 0.3V
Average Output Current (Note 6) 150mA

ESD Ratings
Human Body Model Class 2 (Tested per JESD22-A114E) 2000V
Machine Model Class B (Tested per JESD22-A115-A) . . . 200V
Charged Device Model Class IV 1000V

Latch-Up
(Tested per JESD-78B; Class 2, Level A)
Output Current . . . . 500 mA

Thermal Information

Thermal Resistance (Typical) θ_{JA} (°C/W) θ_{JC} (°C/W)
  8 Ld TDFN Package (Notes 4, 5). . .   44   3
  8 Ld EPSOIC Package (Notes 4, 5) .   42   3
Max Power Dissipation at +25°C in Free Air 2.27W
Max Power Dissipation at +25°C with Copper Plane . . .33.3W
Storage Temperature Range . . . . -65°C to +150°C
Operating Junction Temp Range . . . . -40°C to +125°C
Pb-Free Reflow Profile . . . . see link below
  http://www.intersil.com/pbfree/Pb-FreeReflow.asp

Maximum Recommended Operating Conditions

Junction Temperature. . . . . -40°C to +125°C
Supply Voltage, V_{DD} Relative to GND . . . . 4.5V to 16V
Logic Inputs (INA, INB) . . . . 0V to VDD
Outputs (OUTA, OUTB). . . . . 0V to VDD

CAUTION: Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

NOTES:

4. θ_{JA} is measured in free air with the component mounted on a high effective thermal conductivity test board with "direct attach" features. See Tech Brief TB379 for details.

5. For θ_{JC}, the "case temp" location is the center of the exposed metal pad on the package underside.

6. The average output current, when driving a power MOSFET or similar capacitive load, is the average of the rectified output current. The peak output currents of this driver are self limiting by transconductance or $r_{DS(ON)}$ and do not required any external components to minimize the peaks. If the output is driving a non-capacitive load, such as an LED, maximum output current must be limited by external means to less than the specified absolute maximum.

DC Electrical Specifications
V_{DD} = 12V, GND = 0V, No load on OUTA or OUTB, unless otherwise specified.
**Boldface limits apply over the operating junction temperature range, -40°C to +125°C.**

PARAMETERS	SYMBOL	TEST CONDITIONS	T_J = +25°C			T_J = -40°C to +125°C		UNITS
			MIN	TYP	MAX	MIN (Note 7)	MAX (Note 7)	
POWER SUPPLY								
Voltage Range	V_{DD}		-	-	-	**4.5**	**16**	V
V_{DD} Quiescent Current	I_{DD}	INx = GND	-	5	-	-	-	mA
		INA = INB = 1MHz, square wave	-	25		-	-	mA
UNDERVOLTAGE								
VDD Undervoltage Lock-out (Note 9)	V_{UV}	INA = INB = True (Note 10)	-	3.3	-	-	-	V
Hysteresis			-	~25	-	-	-	mV
INPUTs								
Input Range for INA, INB	V_{IN}		-	-	-	**GND**	**V_{DD}**	V
Logic 0 Threshold for INA, INB	V_{IL}	Nominally 37% x 3.3V	-	1.22	-	**1.12**	**1.32**	V
Logic 1 Threshold for INA, INB	V_{IH}	Nominally 63% x 3.3V	-	2.08	-	**1.98**	**2.18**	V
Input Capacitance of INA, INB (Note 8)	C_{IN}		-	2	-	-	-	pF
Input Bias Current for INA, INB	I_{IN}	GND<V_{IN}<V_{DD}	-	-	-	**-10**	**+10**	µA

DC Electrical Specifications V_{DD} = 12V, GND = 0V, No load on OUTA or OUTB, unless otherwise specified. **Boldface limits apply over the operating junction temperature range, -40°C to +125°C. (Continued)**

PARAMETERS	SYMBOL	TEST CONDITIONS	T_J = +25°C			T_J = -40°C to +125°C		UNITS
			MIN	TYP	MAX	MIN (Note 7)	MAX (Note 7)	
OUTPUTS								
High Level Output Voltage	V_{OHA} V_{OHB}		-	-	-	**V_{DD} - 0.1**	**V_{DD}**	V
Low Level Output Voltage	V_{OLA} V_{OLB}		-	-	-	**GND**	**GND + 0.1**	V
Peak Output Source Current	I_O	V_O (initial) = 0V, C_{LOAD} = 10nF	-	-6	-	-	-	A
Peak Output Sink Current	I_O	V_O (initial) =12V, C_{LOAD} = 10nF	-	+6	-	-	-	A

NOTES:

7. Parameters with MIN and/or MAX limits are 100% tested at +25°C, unless otherwise specified. Temperature limits established by characterization and are not production tested.

8. This parameter is taken from the simulation models for the input FET. The actual capacitance on this input will be dominated by the PCB parasitic capacitance.

9. A 200μs delay further inhibits the release of the output state when the UV positive going threshold is crossed.

10. The true state of a specific part number is defined by the input logic symbol.

AC Electrical Specifications V_{DD} = 12V, GND = 0V, No Load on OUTA or OUTB, Unless Otherwise Specified. **Boldface limits apply over the operating junction temperature range, -40°C to +125°C.**

PARAMETERS	SYMBOL	TEST CONDITIONS /NOTES	T_J = +25°C			T_J = -40°C to +125°C		UNITS
			MIN	TYP	MAX	MIN	MAX	
Output Rise Time (see Figure 2)	t_R	C_{LOAD} = 10nF, 10% to 90%	-	20	-	-	40	ns
Output Fall Time (see Figure 2)	t_F	C_{LOAD} = 10nF, 90% to 10%	-	20	-	-	40	ns
Output Rising Edge Propagation Delay for Non-Inverting Inputs (see Figure 1)	t_{RDLYn}	No load	-	25	-	-	50	ns
Output Rising Edge Propagation Delay with Inverting Inputs (see Figure 1)	t_{RDLYi}	No load	-	25	-	-	50	ns
Output Falling Edge Propagation Delay with Non-Inverting Inputs (see Figure 1)	t_{FDLYn}	No load	-	25	-	-	50	ns
Output Falling Edge Propagation Delay with Inverting Inputs (see Figure 1)	t_{FDLYi}	No load	-	25	-	-	50	ns
Rising Propagation Matching (see Figure 1)	t_{RM}		-	<1ns	-	-	-	ns
Falling Propagation Matching (see Figure 1)	t_{FM}		-	<1ns	-	-	-	ns
Miller Plateau Sink Current (See Test Circuit Figure 3)	$-I_{MP}$	V_{DD} = 10V, V_{MILLER} = 5V	-	6	-	-	-	A
	$-I_{MP}$	V_{DD} = 10V, V_{MILLER} = 3V	-	4.7	-	-	-	A
	$-I_{MP}$	V_{DD} = 10V, V_{MILLER}= 2V	-	3.7	-	-	-	A

AC Electrical Specifications
V_{DD} = 12V, GND = 0V, No Load on OUTA or OUTB, Unless Otherwise Specified.
**Boldface limits apply over the operating junction temperature range,
-40°C to +125°C. (Continued)**

PARAMETERS	SYMBOL	TEST CONDITIONS /NOTES	T_J = +25°C			T_J = -40°C to +125°C		UNITS
			MIN	TYP	MAX	MIN	MAX	
Miller Plateau Source Current (See Test Circuit Figure 4)	I_{MP}	V_{DD} = 10V, V_{MILLER} = 5V	-	5.2	-	-	-	A
	I_{MP}	V_{DD} = 10V, V_{MILLER} = 3V	-	5.8	-	-	-	A
	I_{MP}	V_{DD} = 10V, V_{MILLER} = 2V	-	6.9	-	-	-	A

Test Waveforms and Circuits
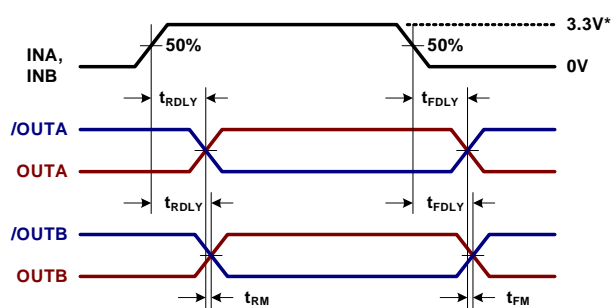
* logic levels: A option = 3.3V, B option = 5.0V, C option = VDD

FIGURE 1. PROP DELAYS AND MATCHING
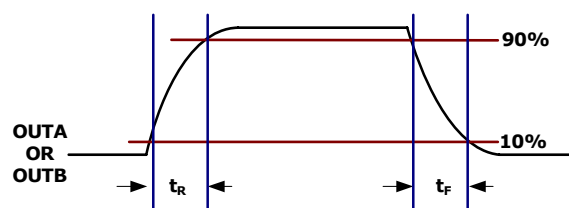
FIGURE 2. RISE/FALL TIMES
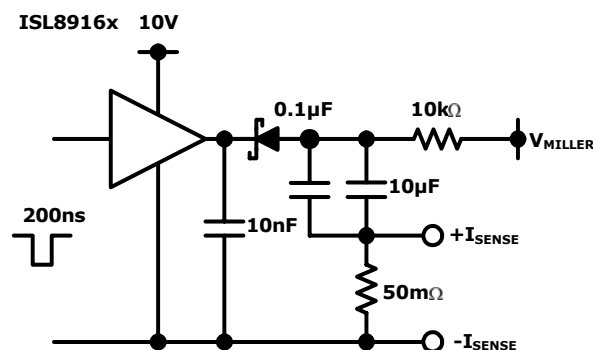
FIGURE 3. MILLER PLATEAU SINK CURRENT TEST CIRCUIT
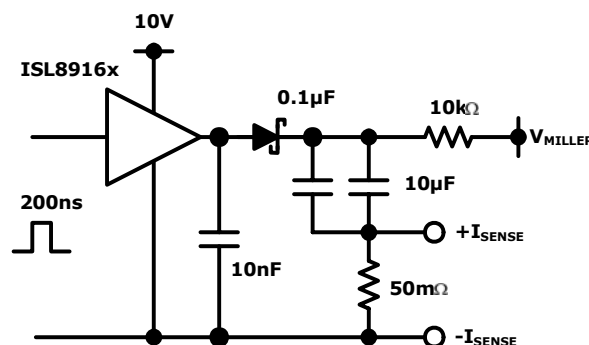
FIGURE 4. MILLER PLATEAU SOURCE CURRENT TEST CIRCUIT

Test Waveforms and Circuits
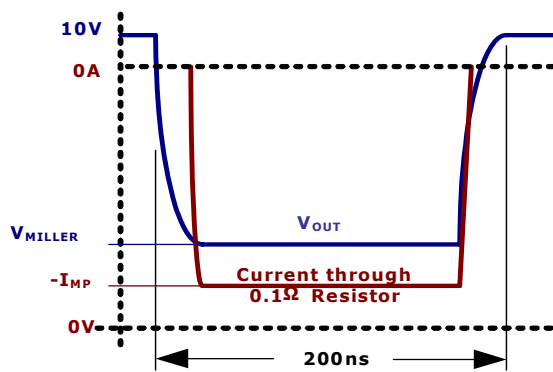
FIGURE 5. MILLER PLATEAU SINK CURRENT
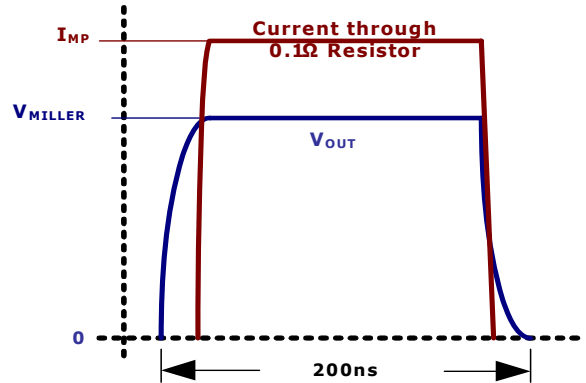
FIGURE 6. MILLER PLATEAU SOURCE CURRENT

Typical Performance Curves
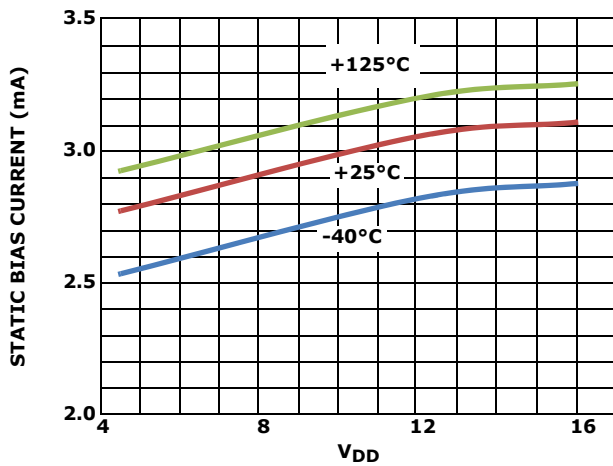
FIGURE 7. I_{DD} vs V_{DD} (STATIC)
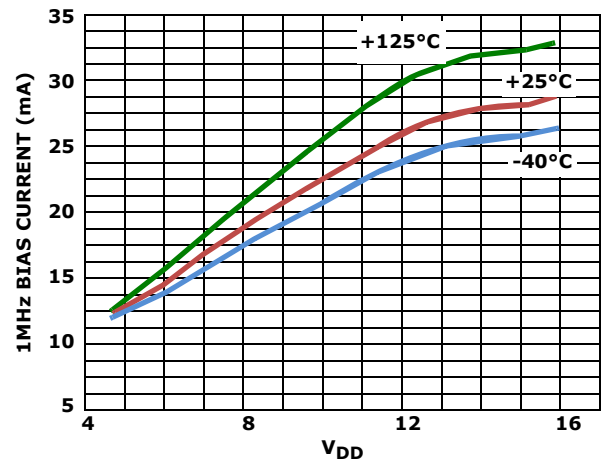
FIGURE 8. I_{DD} vs V_{DD} (1 MHz)
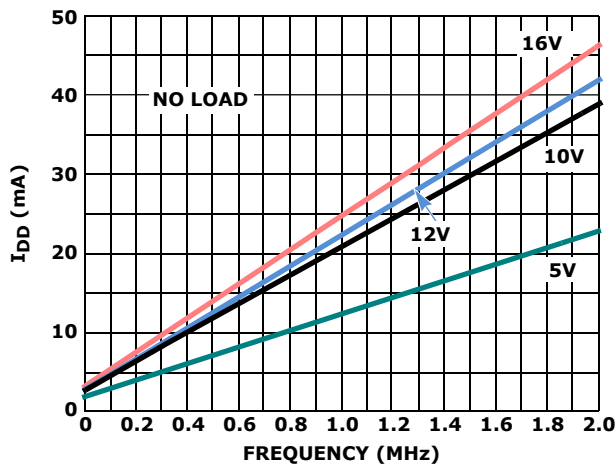
FIGURE 9. I_{DD} vs FREQUENCY (+25°C)
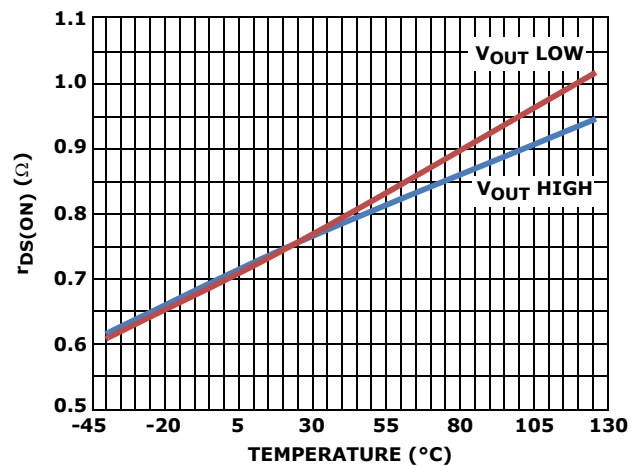
FIGURE 10. $r_{DS(ON)}$ vs TEMPERATURE

intersil

Typical Performance Curves (Continued)
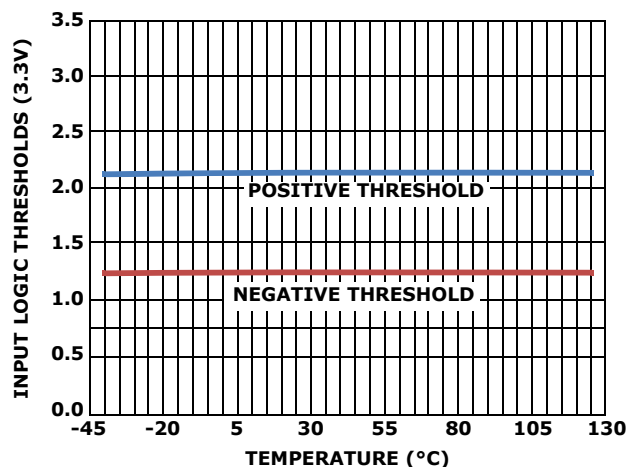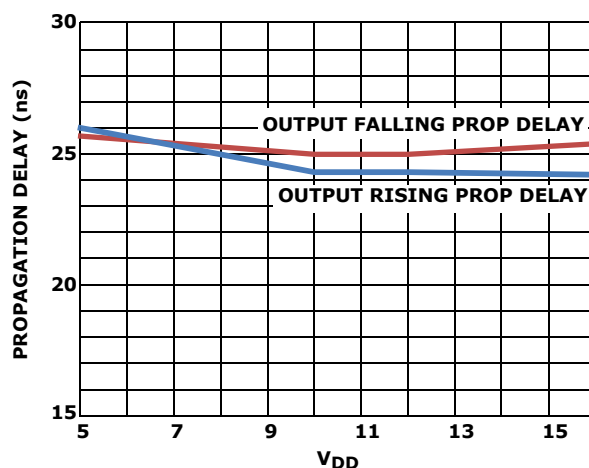

FIGURE 11. INPUT THRESHOLDS
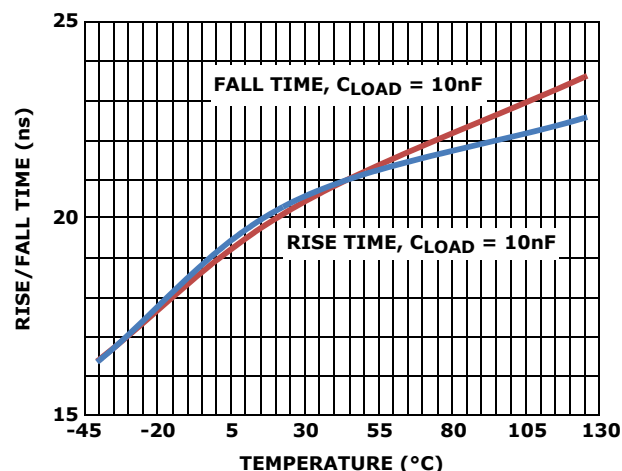
FIGURE 12. OUTPUT RISE/FALL TIME

FIGURE 13. PROPAGATION DELAY vs V$_{DD}$

Functional Description

Overview

The ISL89160, ISL89161, ISL89162 drivers incorporate several features including precision input logic thresholds, undervoltage lock-out, and fast rising high output drive currents.

The precision input thresholds facilitate the use of an external RC network to delay the rising or falling propagation of the driver output. This is a useful feature to create dead times for bridge applications to prevent shoot through.

To prevent unexpected glitches on the output of the ISL89160, ISL89161, ISL89162 during power-on or power-off when V$_{DD}$ is very low, the Undervoltage (UV) lock-out prevents the outputs of the ISL89160, ISL89161, ISL89162 driver from turning on. The UV lock-out forces the driver outputs to be low when VDD < ~3.2 VDC regardless of the input logic level.

Fast rising (or falling) output drive current of the ISL89160, ISL89161, ISL89162 minimizes the turn-on (off) delay due to the input capacitance of the driven FET. The switching transition period at the Miller plateau is also minimized by the high drive currents. (See the specified Miller plateau currents in the AC Electrical Specifications on page 5).

Application Information

Precision Thresholds for Time Delays

The nominal input negative transition threshold is 1.22V and the positive transition threshold is 2.08V (37% and 63% of 3.3V).
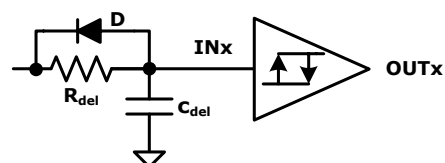

FIGURE 14. DELAY USING RCD NETWORK

In Figure 14, R_{del} and C_{del} delay the rising edge of the input signal. For the falling edge of the input signal, the diode shorts out the resistor resulting in a minimal falling edge delay. If the diode polarity is reversed, the falling edge is delayed and the rising delay is minimal.

The 37% and 63% thresholds were chosen to simplify the calculations for the desired time delays. When using an RC circuit to generate a time delay, the delay is simply T (secs) = R (ohms) x C (farads). Please note that this equation only applies if the input logic voltage amplitude is 3.3V. If the logic high amplitude is higher than 3.3V, the equations in EQ 1 can be used for more precise delay calculations.

$V_H = 5V$ **High level of the logic signal into the RC**

$V_{THRESH} = 63\% \times 3.3V$ **Positive going threshold**

$V_L = 0.1V$ **Low level of the logic signal into the RC**

$R_{del} = 100\Omega$ **Timing values**

$C_{del} = 1nF$

$t_{del} = -R_{del}C_{del} \times LN\left(\dfrac{V_L - V_{THRESH}}{V_H - V_L} + 1\right)$

$t_{del} = 51.731ns$ **Nominal delay time**

(EQ. 1)

In this example, the high input logic voltage is 5V, the positive threshold is 63% of 3.3V and the low level input logic is 0.1V. **Note the rising edge propagation delay of the driver must be added to this value**.

The minimum recommended value of C is 100pF. The parasitic capacitance of the PCB and any attached scope probes will introduce significant delay errors if smaller values are used. Larger values of C will further minimize errors.

Acceptable values of R are primarily effected by the source resistance of the logic inputs. Generally, 100Ω resistors or larger are usable. A practical maximum value, limited by contamination on the PCB, is 1MΩ.

Power Dissipation of the Driver

The power dissipation of the ISL89160, ISL89161, ISL89162 is dominated by the losses associated with the gate charge of the driven bridge FETs and the switching frequency. The internal bias current also contributes to the total dissipation but is usually not significant as compared to the gate charge losses.
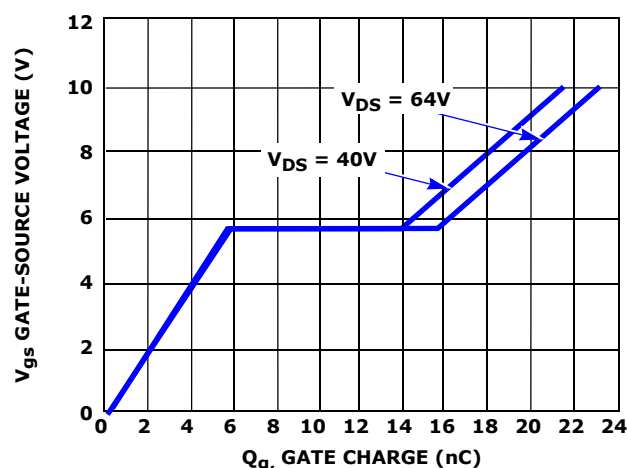

FIGURE 15. MOSFET GATE CHARGE vs GATE VOLTAGE

Figure 15 illustrates how the gate charge varies with the gate voltage in a typical power MOSFET. In this example, the total gate charge for $V_{GS} = 10V$ is 21.5nC when $V_{DS} = 40V$. This is the charge that a driver must source to turn-on the MOSFET and must sink to turn-off the MOSFET.

Equation 2 shows calculating the power dissipation of the driver:

$$P_D = 2 \bullet Q_c \bullet freq \bullet V_{GS} \bullet \frac{R_{gate}}{R_{gate} + r_{DS(ON)}} + I_{DD}(freq) \bullet V_{DD}$$

(EQ. 2)

where:

freq = Switching frequency,

V_{GS} = V_{DD} bias of the ISL89160, ISL89161, ISL89162
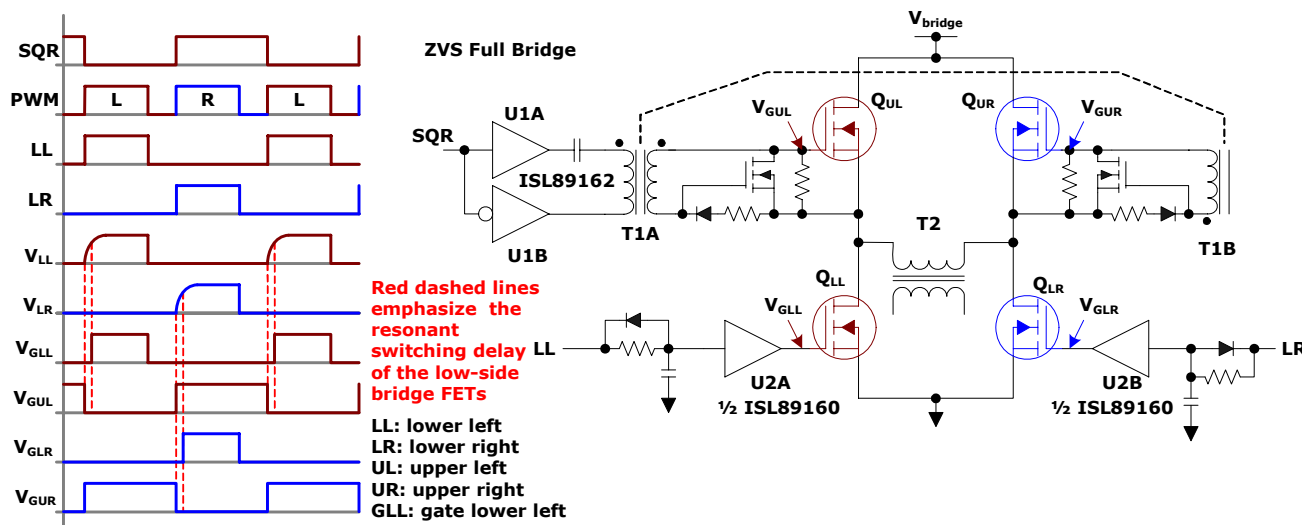
Q_c = Gate charge for V_{GS}

$I_{DD}(freq)$ = Bias current at the switching frequency (see Figure 7)

$r_{DS(ON)}$ = ON-resistance of the driver

R_{gate} = External gate resistance (if any).

Note that the gate power dissipation is proportionally shared with the external gate resistor and the output $r_{DS(ON)}$. When sizing an external gate resistor, do not overlook the power dissipated by this resistor.

Typical Application Circuit

Red dashed lines emphasize the resonant switching delay of the low-side bridge FETs

LL: lower left
LR: lower right
UL: upper left
UR: upper right
GLL: gate lower left

This is an example of how the ISL89160, ISL89161, ISL89162, MOSFET drivers can be applied in a zero voltage switching full bridge. Two main signals are required: a 50% duty cycle square wave (SQR) and a PWM signal synchronized to the edges of the SQR input. An ISL89162 is used to drive T1 with alternating half cycles driving Q_{UL} and Q_{UR}. An ISL89160 is used to drive Q_{LL} and Q_{LR} also with alternating half cycles. Unlike the two high-side bridge FETs, the two low side bridge FETs are turned on with a rising edge delay. The delay is setup by the RCD network on the inputs to the ISL89160. The duration of the delay is chosen to turn on the low-side FETs when the voltage on their respective drains is at the resonant valley. For a complete description of the ZVS topology, refer to AN1603 "ISL6752_54 Evaluation Board Application Note".

General PCB Layout Guidelines

The AC performance of the ISL89160, ISL89161, ISL89162 depends significantly on the design of the PC board. The following layout design guidelines are recommended to achieve optimum performance:

• Place the driver as close as possible to the driven power FET.

• Understand where the switching power currents flow. The high amplitude di/dt currents of the driven power FET will induce significant voltage transients on the associated traces.

• Keep power loops as short as possible by paralleling the source and return traces.

• Use planes where practical; they are usually more effective than parallel traces.

• Avoid paralleling high amplitude di/dt traces with low level signal lines. High di/dt will induce currents and consequently, noise voltages in the low level signal lines.

• When practical, minimize impedances in low level signal circuits. The noise, magnetically induced on a 10k resistor, is 10x larger than the noise on a 1k resistor.

• Be aware of magnetic fields emanating from transformers and inductors. Gaps in these structures are especially bad for emitting flux.

• If you must have traces close to magnetic devices, align the traces so that they are parallel to the flux lines to minimize coupling.

• The use of low inductance components such as chip resistors and chip capacitors is highly recommended.

• Use decoupling capacitors to reduce the influence of parasitic inductance in the VDD and GND leads. To be effective, these caps must also have the shortest possible conduction paths. If vias are used, connect several paralleled vias to reduce the inductance of the vias.

• It may be necessary to add resistance to dampen resonating parasitic circuits especially on OUTA and OUTB. If an external gate resistor is unacceptable, then the layout must be improved to minimize lead inductance.

• Keep high dv/dt nodes away from low level circuits. Guard banding can be used to shunt away dv/dt injected currents from sensitive circuits. This is especially true for control circuits that source the input signals to the ISL89163/164/165.

• Avoid having a signal ground plane under a high amplitude dv/dt circuit. This will inject di/dt currents into the signal ground paths.

• Do power dissipation and voltage drop calculations of the power traces. Many PCB/CAD programs have built in tools for calculation of trace resistance.

- Large power components (Power FETs, Electrolytic caps, power resistors, etc.) will have internal parasitic inductance which cannot be eliminated. This must be accounted for in the PCB layout and circuit design.

- If you simulate your circuits, consider including parasitic components especially parasitic inductance.

General EPAD Heatsinking Considerations

The thermal pad is electrically connected to the GND supply through the IC substrate. The epad of the ISL89163/164/165 has two main functions: to provide a quiet Gnd for the input threshold comparators and to provide heat sinking for the IC. The EPAD must be connected to a ground plane and no switching currents from the driven FET should pass through the ground plane under the IC.

Figure 16 is a PCB layout example of how to use vias to remove heat from the IC through the epad.
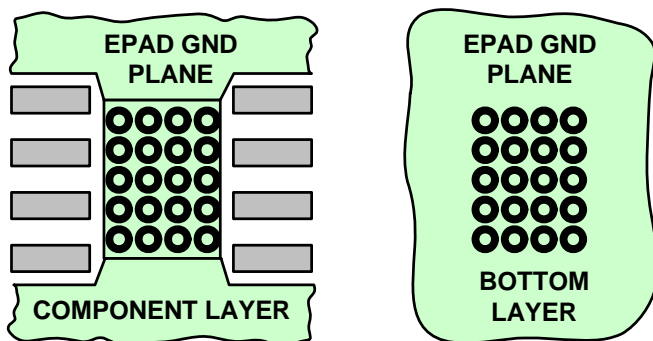
FIGURE 16. TYPICAL PCB PATTERN FOR THERMAL VIAS

For maximum heatsinking, it is recommended that a ground plane, connected to the EPAD, be added to both sides of the PCB. A via array, within the area of the EPAD, will conduct heat from the EPAD to the gnd plane on the bottom layer. The number of vias and the size of the gnd planes required for adequate heatsinking is determined by the power dissipated by the ISL89160, ISL89161, ISL89162, the air flow and the maximum temperature of the air around the IC.

Revision History

The revision history provided is for informational purposes only and is believed to be accurate, but not warranted. Please go to web to make sure you have the latest Rev.

DATE	REVISION	CHANGE
11/2/10	FN7719.0	Initial Release

Products

Intersil Corporation is a leader in the design and manufacture of high-performance analog semiconductors. The Company's products address some of the industry's fastest growing markets, such as, flat panel displays, cell phones, handheld products, and notebooks. Intersil's product families address power management and analog signal processing functions. Go to www.intersil.com/products for a complete list of Intersil product families.

*For a complete listing of Applications, Related Documentation and Related Parts, please see the respective device information page on intersil.com: ISL89160, ISL89161, ISL89162

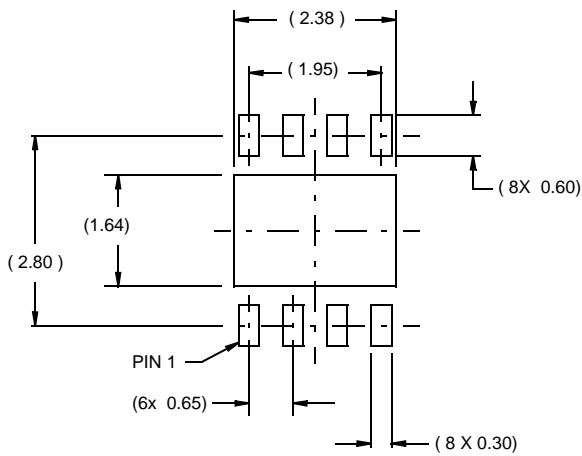To report errors or suggestions for this datasheet, please go to www.intersil.com/askourstaff

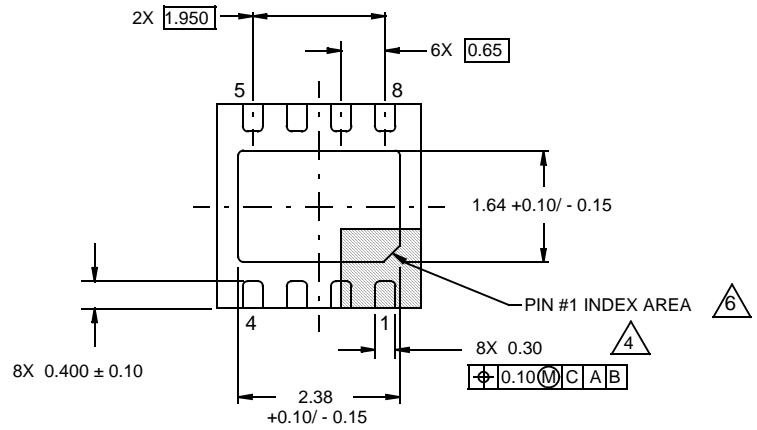FITs are available from our website at http://rel.intersil.com/reports/sear

Package Outline Drawing
L8.3x3I
8 LEAD THIN DUAL FLAT NO-LEAD PLASTIC PACKAGE
Rev 1 6/09

TOP VIEW

BOTTOM VIEW

TYPICAL RECOMMENDED LAND PATTERN

SIDE VIEW

DETAIL "X"
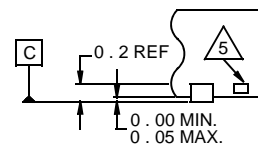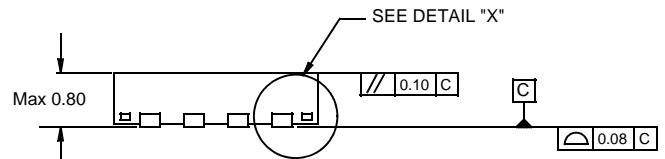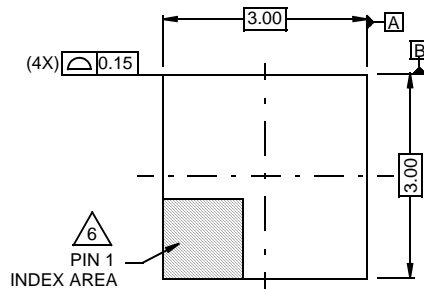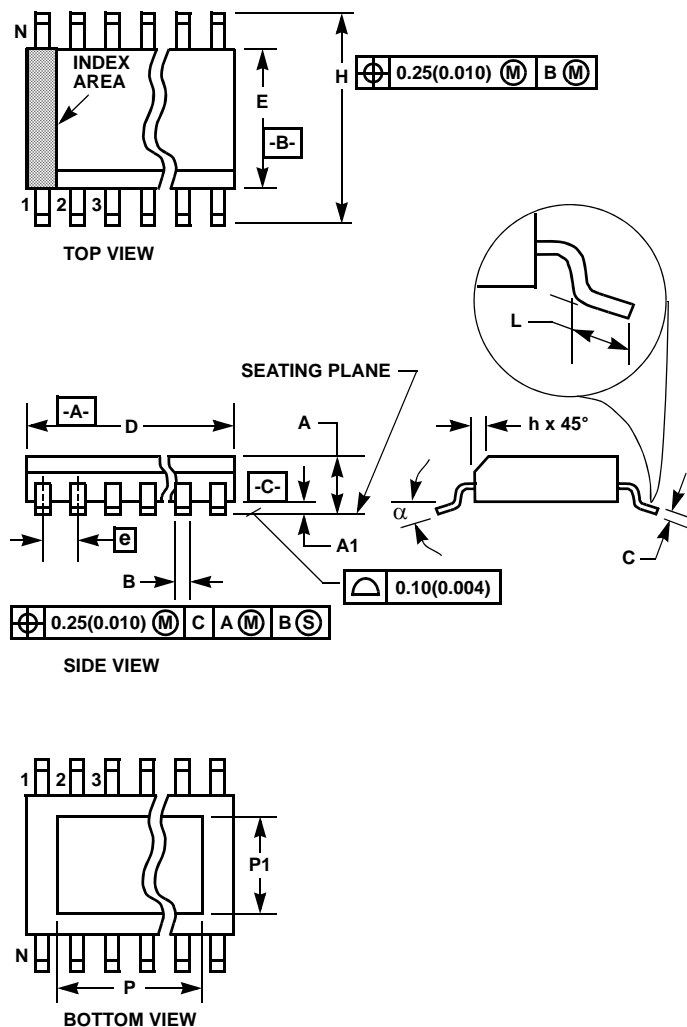
NOTES:

1. Dimensions are in millimeters.
   Dimensions in ( ) for Reference Only.

2. Dimensioning and tolerancing conform to AMSE Y14.5m-1994.

3. Unless otherwise specified, tolerance : Decimal ± 0.05

4. Dimension applies to the metallized terminal and is measured between 0.15mm and 0.30mm from the terminal tip.

5. Tiebar shown (if present) is a non-functional feature.

6. The configuration of the pin #1 identifier is optional, but must be located within the zone indicated. The pin #1 identifier may be either a mold or mark feature.

Small Outline Exposed Pad Plastic Packages (EPSOIC)

TOP VIEW

SIDE VIEW

BOTTOM VIEW

M8.15D
8 LEAD NARROW BODY SMALL OUTLINE EXPOSED PAD PLASTIC PACKAGE

SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	0.059	0.067	1.52	1.72	-
A1	0.003	0.009	0.10	0.25	-
B	0.0138	0.0192	0.36	0.46	9
C	0.0075	0.0098	0.19	0.25	-
D	0.189	0.196	4.80	4.98	3
E	0.150	0.157	3.811	3.99	4
e	0.050 BSC		1.27 BSC		-
H	0.230	0.244	5.84	6.20	-
h	0.010	0.019	0.25	0.50	5
L	0.016	0.050	0.41	1.27	6
N	8		8		7
α	0°	8°	0°	8°	-
P	0.118	0.137	3.00	3.50	11
P1	0.078	0.099	2.00	2.50	11

Rev. 0 5/07

NOTES:

1. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication Number 95.

2. Dimensioning and tolerancing per ANSI Y14.5M-1982.

3. Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusion and gate burrs shall not exceed 0.15mm (0.006 inch) per side.

4. Dimension "E" does not include interlead flash or protrusions. Interlead flash and protrusions shall not exceed 0.25mm (0.010 inch) per side.

5. The chamfer on the body is optional. If it is not present, a visual index feature must be located within the crosshatched area.

6. "L" is the length of terminal for soldering to a substrate.

7. "N" is the number of terminal positions.

8. Terminal numbers are shown for reference only.

9. The lead width "B", as measured 0.36mm (0.014 inch) or greater above the seating plane, shall not exceed a maximum value of 0.61mm (0.024 inch).

10. Controlling dimension: MILLIMETER. Converted inch dimensions are not necessarily exact.

11. Dimensions "P" and "P1" are thermal and/or electrical enhanced variations. Values shown are maximum size of exposed pad within lead count and body size.